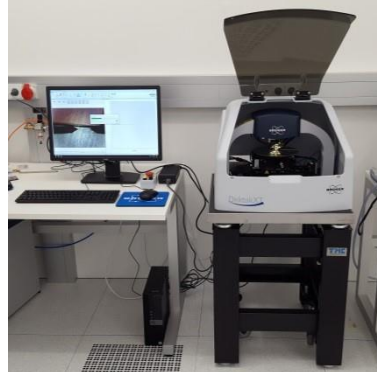


METROLOGY

Stylus Profiler

Manufacturer: Bruker

Model: Dektak XT-A Surface Profiler



General Description:

The Dektak XT surface profiler is an advanced thin and thick film step height measurement tool. In addition, the Dektak XT allows characterizing surface topography, waviness and roughness of the samples in the nanometer range. The system can also produce three-dimensional measurements and analyses with 3D mapping.

Key Specifications:

- Vertical resolution 1 Å (digital resolution @ 6.55 µm range)
- Step height repeatability 5 Å, 1 sigma on steps $\leq 1 \mu\text{m}$ (30 scans using a 12.5 µm stylus)
- Vertical range 1 mm
- Motorized X/Y stage with 6 inches of travel, motorized 360 degree rotation
- Stitching for up to 200 mm scans
- 3D map collection and extensive data analysis
- Max. Sample Thickness 50 mm (Max. Wafer Size 200 mm (8 inch))

Availability	Use allowed for all researchers with permission
Location	Cleanroom C7 Europastraße 12 9524 Villach
Responsibles / Contact	Dr. Adrien Piot / Dr. Ali Roshanghias Tel.:+43 4242 56300 264 Tel.:+43 4242 56300 256